



Fault Identification and Prognosis for Electromechanical Systems

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Message from the Guest Editors

Dear Colleagues,

Fault identification and failure prognosis for electromechanical systems have become very important for most industrial sectors and for academic research. Fault identification includes fault detection, fault isolation, estimation of failure modes of faults, and fault severity estimation.

This Special Issue's scope is on novel research and developments, related to:

- Fault detection;
- Fault isolation;
- Estimation of failure modes of faults;
- Fault severity estimation;
- Failure prognosis.

This Special Issue will not cover non-novel “case study” papers and papers, related to software fault prediction. Potential authors need to make clear statements of paper novelties, which should be based on comprehensive state-of-the-art reviews.

Prof. Dr. Len Gelman
Guest Editor





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Message from the Editor-in-Chief

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